



H. Display and Imaging Technologies 분과

2021년 1월 29일(금), 09:00-10:30 / 채널 D

[FD1-H] CMOS Image Sensor & X-ray Detector

좌장: 권혁인 교수 (중앙대학교), 박진성 교수 (한양대학교)

<p>FD1-H-1 09:00-09:30</p>	<p>[초청] Study on the Noise in CMOS Image Sensor; How to Improve It Manlyun Ha <i>CIS Process Development Team, Fab², DB HiTek</i></p>
<p>FD1-H-2 09:30-10:00</p>	<p>[초청] Flat Panel X-ray Detectors and Their Applications Kyung Hun Yoon <i>Vieworks Co., Ltd.</i></p>
<p>FD1-H-3 10:00-10:15</p>	<p>Design Consideration of In-pixel Bias Transistor in Voltage-Domain Global Shutter CMOS Image Sensor Dae-Hoon Kim, Dongseok Cho, Seung Sik Kim, Jonghyun Go, Jae-kyu Lee, and Chang-Rok Moon <i>Samsung Electronics Co., Ltd.</i></p>
<p>FD1-H-4 10:15-10:30</p>	<p>The Impact of the Sidewall Oxidation in Pixel Transistors on the Image Performance Manlyun Ha, YoungHwan Hyun, ChangHun Han, and YongChan Kim <i>CIS Process Development Team, Fab², DB HiTek</i></p>